

Anritsu Company to Present Series of Papers on High Frequency Testing at EDI CON 2014

— *Global Test Leader to Discuss Techniques that Address Challenges Associated with Materials Measurements and Characterizing Devices Operating at Microwave, Millimeter Wave and THz Frequencies using Vector Network Analyzers* —

Morgan Hill, CA – April 2, 2014 – Anritsu Company, a global leader in communications test solutions, announces it will participate in a series of presentations at EDI CON 2014, to be held April 8-10 at the Beijing International Convention Center in Beijing, China. The three presentations given by Anritsu representatives will answer many of the questions engineers face when characterizing devices that operate at microwave and millimeter wave (mm-wave) frequencies.

Stable On-wafer Broadband Device Characterization to 110 GHz

Bob Buxton, product marketing manager for Anritsu, will give a presentation on Tuesday, April 8. The session will cover measurement issues faced by device characterization engineers and solutions available to make S-parameter measurements using a VectorStar™-based broadband vector network analysis system from 70 kHz to 110 GHz. New work extending this capability to 145 GHz will also be described.

Advances in Quasi-optical and Free-space mm-wave and THz-region Materials Measurements

This paper, presented by Dr. Jon Martens of Anritsu, and Jeffery Hesler and Alex Arsenovic of Virginia Diodes, Inc., will examine techniques ranging from free-space measurements in the 100 GHz range to quasi-optical measurements at 1 THz. In all of these measurements, the calibration processes, required sample morphologies and expected repeatability levels will be discussed. The session is scheduled for Thursday, April 10.

Uncertainty and Stability in True Differential-drive Measurements

Dr. Martens will lead a second session on Thursday, April 10 that will focus on differential-drive measurements. The characterization and model development for many high-speed components

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may include differential return loss, transmission, and mode conversion measurements under real-world drive conditions. As such, true differential drive at large signal levels is often needed and measurements can be a challenge. The presentation will discuss a highly stable method of making these measurements and how understanding uncertainty degradation can help minimize re-calibrations and increase confidence in the data.

About Anritsu

Anritsu Company (www.anritsu.com) is the United States subsidiary of Anritsu Corporation, a global provider of innovative communications test and measurement solutions for more than 110 years. Anritsu provides solutions for existing and next-generation wired and wireless communication systems and operators. Anritsu products include wireless, optical, microwave/RF, and digital instruments as well as operations support systems for R&D, manufacturing, installation, and maintenance. Anritsu also provides precision microwave/RF components, optical devices, and high-speed electrical devices for communication products and systems. With offices throughout the world, Anritsu sells in over 90 countries with approximately 4,000 employees.

To learn more visit www.anritsu.com.

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